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|-----------------------------------|--|---------------------------------------|-----------------------------------------------------------------|-------------|
| Notice of References Cited | | Application/Control No. 10/813,682 | Applicant(s)/Patent Under Reexamination VAN DER PASCH ET AL. | |
| | | Examiner Bernard E. Souw | Art Unit 2881 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|------------------------|----------------|
| | A | US-2005/0218342 | 10-2005 | Van Der Pasch et al. | 250/492.2 |
| | B | US-2004/0130690 | 07-2004 | Koren et al. | 355/053 |
| | C | US-2004/0165168 | 08-2004 | Botma, Hako | 355/067 |
| | D | US-6,924,885 | 08-2005 | Botma, Hako | 355/71 |
| | E | US-6,844,918 | 01-2005 | Navarro Y Koren et al. | 355/53 |
| | F | US-2006/0103033 | 05-2006 | Van Haren et al. | 257/797 |
| | G | US-2006/0072108 | 04-2006 | Onvlee et al. | 356/239.8 |
| | H | US-2006/0072107 | 04-2006 | Onvlee et al. | 356/239.8 |
| | I | US-2005/0157383 | 07-2005 | Tichenor et al. | 359/359 |
| | J | US-2004/0207836 | 10-2004 | Chhibber et al. | 356/237.4 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

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